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Sakai, K.; Nakamura, K.;  
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the 1990 International Conference on , 5-7 Mar 1990  
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Wakil, J.A.; Ho, P.S.;  
Advanced Packaging, IEEE Transactions on [see also Components,  
Packaging and Manufacturing Technology, Part B: Advanced  
Packaging, IEEE Transactions on] , Volume: 24 Issue: 1 , Feb 2001  
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